

An Iterative Feature Filter for Sensor Timeseries in Pervasive Computing Applications

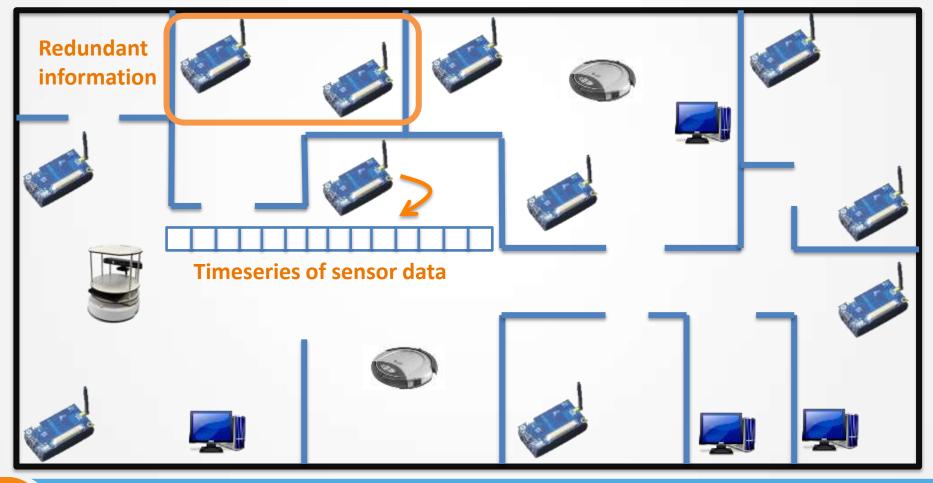
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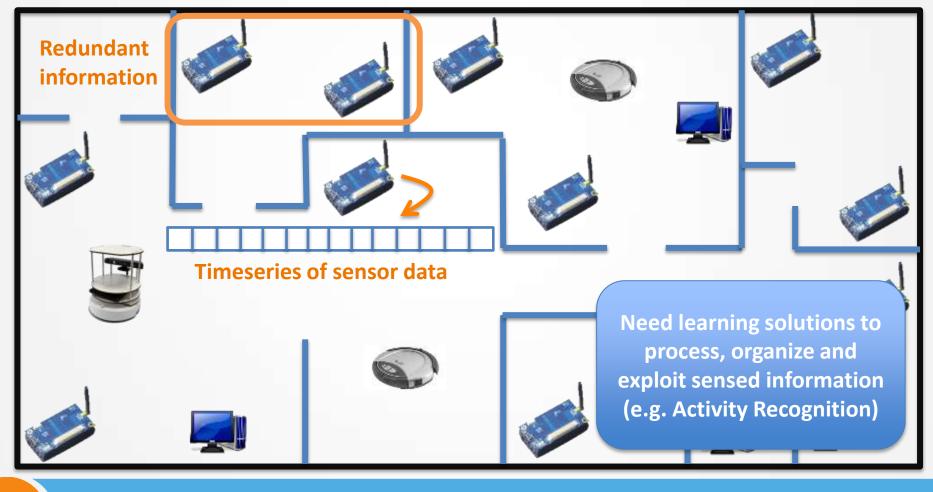
The Application Context

Pervasive computing



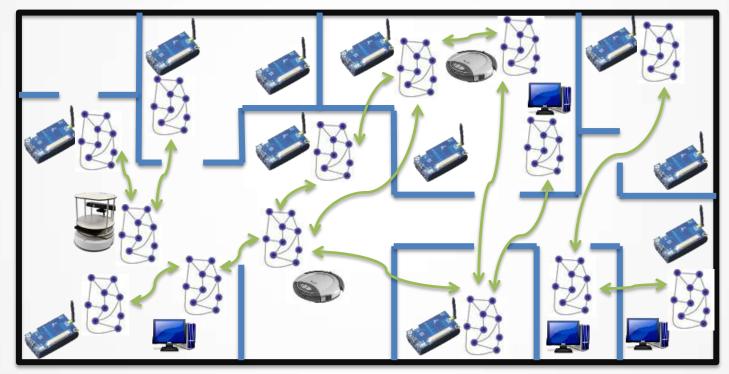
The Application Context

Pervasive computing



The RUBICON Approach

A distributed learning system comprising cooperating Echo State Networks embedded on the network devices



Incremental deployment of new learning tasks during system operation to account for changing environment conditions and new user habits

The Feature Selection Challenge

- Feature selection is required to
 - Reduce computational and communication cost for sensor information processing
 - Suppress redundant/irrelevant information depleting predictive performance
- Application specific requirements
 - Timeseries data
 - Heterogeneous sensor information
 - Automatized and computationally efficient

Lack of significant results in the context of open-ended discovery from real-world sensor-rich environments

Iterative Cross-Correlation Filter (ICF)

- Forward selection-elimination procedure to filter redundant features
- Redundancy is measured by normalized crosscorrelation

$$\overline{\phi}^*_{x^1x^2} = \max_{\tau} \left| \overline{\phi}_{x^1x^2}(\tau) \right|$$

- Based on the following intuition
 - 1. Select variables not correlated with any other features
 - 2. Variables correlated with all currently selected variables are candidates for elimination.
 - If left with mutually correlated variables, maintain those less correlated with selected features

ICF Algorithm

I. Compute the DxD feature redundancy matrix **R** 0

()

0

0

0 0

0

0

0

0

- R_{ij} = 1, if features i and j are redundant
- R_{ij} = 0, otherwise
- II. While unselected/undeleted features exist in R do
 - a. Rule 0 Select completely uncorrelated features
 - b. Rule 1 Delete completely correlated features
 - c. Rule 2 If **R** contains only ones select less correlated feature
 - d. Rule 3 If stuck, pick one feature for selection and one for deletion

ICF Algorithm

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$$O(N \cdot (D^2 \cdot T^{max}) + D)$$

$$\downarrow \qquad \downarrow \qquad \downarrow$$
samples features length

0 0

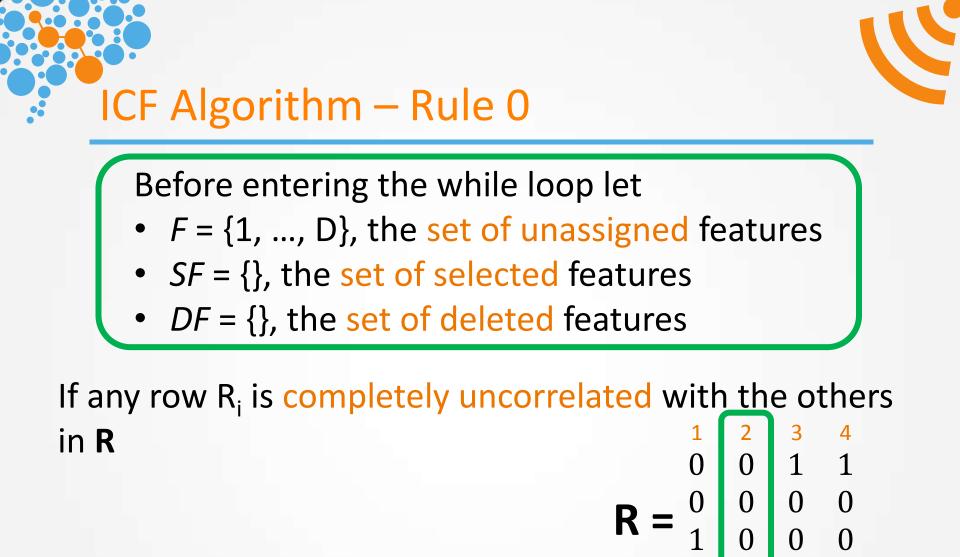
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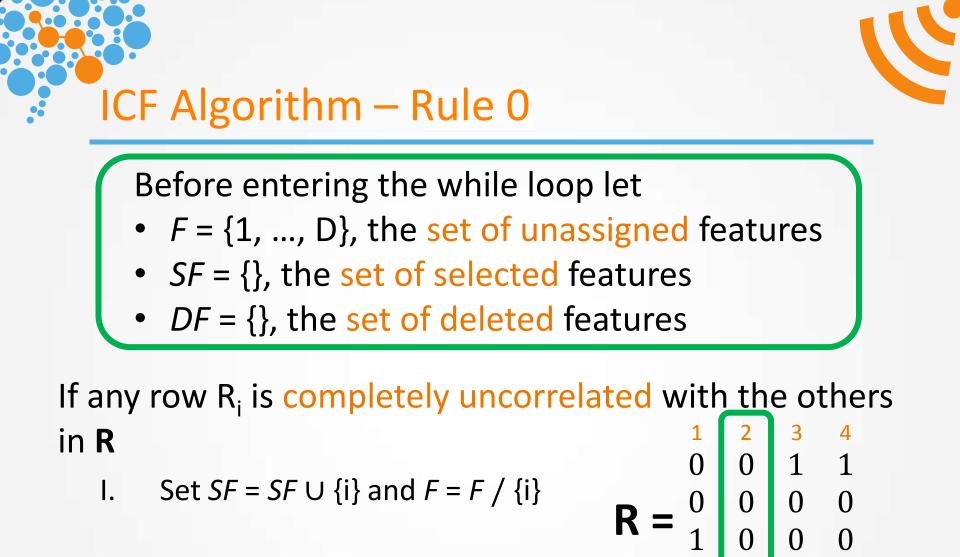
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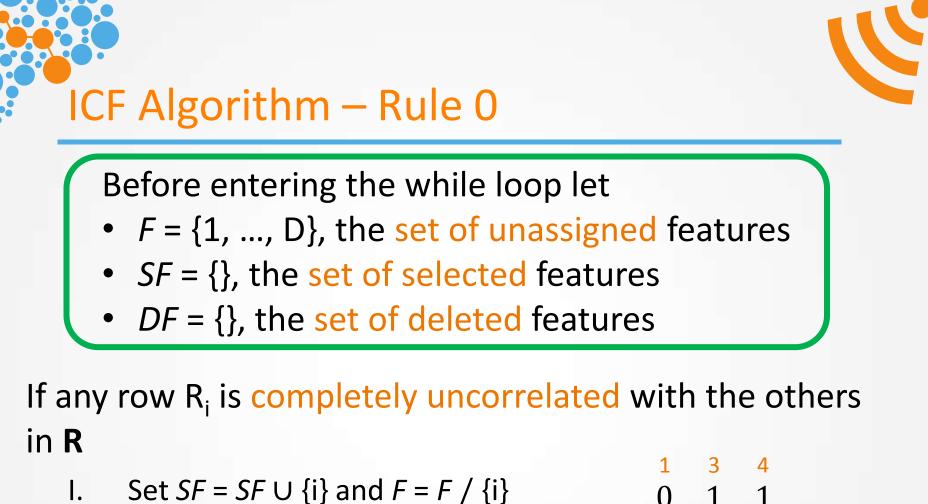
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0





F = {1,3,4}, SF = {2}, DF = {}



II. Remove i-th row/col from R

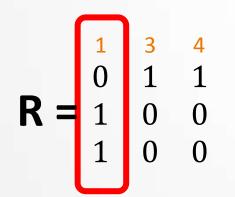
 $\mathbf{R} = \begin{bmatrix} 1 & 3 & 4 \\ 0 & 1 & 1 \\ 1 & 0 & 0 \\ 1 & 0 & 0 \end{bmatrix}$

 $F = \{1,3,4\}, SF = \{2\}, DF = \{\}$



If any row R_i is completely correlated with others in **R** and there is at least 1 non completely correlated feature

I. Set $DF = DF \cup \{i\}$ and $F = F / \{i\}$

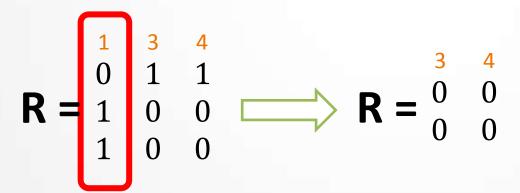


 $F = \{3,4\}, SF = \{2\}, DF = \{1\}$



If any row R_i is completely correlated with others in **R** and there is at least 1 non completely correlated feature

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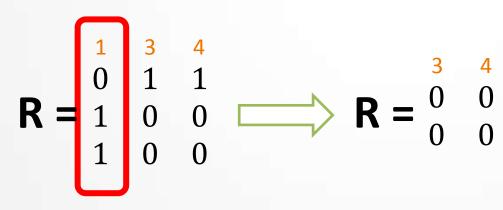
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If any row R_i is completely correlated with others in **R** and there is at least 1 non completely correlated

feature

- I. Set $DF = DF \cup \{i\}$ and $F = F / \{i\}$
- II. Remove i-th row/col from **R**



F = {} SF = {2,3,4}, DF = {1}

RULE 0 will

fire again at

next iteration

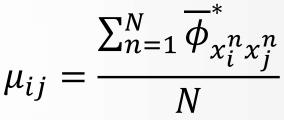
 $F = \{3,4\}, SF = \{2\}, DF = \{1\}$

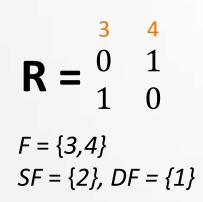


Rule 2

If **R** contains only ones off-diagonal

I. Pick feature i in *F* that is less correlated with those already in *SF*

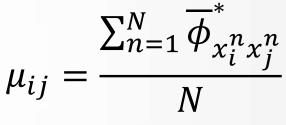


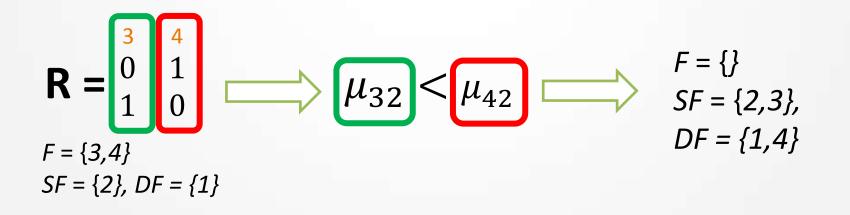




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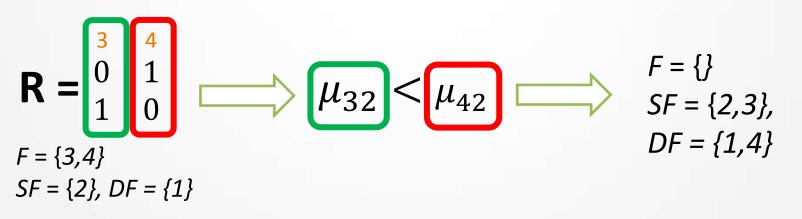






If **R** contains only ones off-diagonal

- Pick feature i in F that is less correlated with those already in SF $\frac{\sum_{n=1}^{N} \overline{\phi}_{x_{i}^{n} x_{j}^{n}}^{*}}{N}$
- Set $SF = SF \cup \{i\}$ and $F = F / \{i\}$ П.
- Set $DF = DF \cup F$ and $F = \{\}$
- IV. Terminate while loop



 μ_{ij}





If neither RULE 1 nor RULE 2 fire,

I. Pick feature i in *F* that is minimally correlated with features in *SF*

$$\mu_{42} < \mu_{32}$$





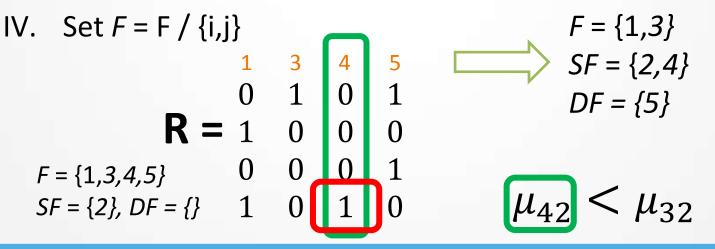
If neither RULE 1 nor RULE 2 fire,

- I. Pick feature i in *F* that is minimally correlated with features in *SF*
- II. Pick feature j from those correlated to i that is also the maximally correlated with selected features in *SF*

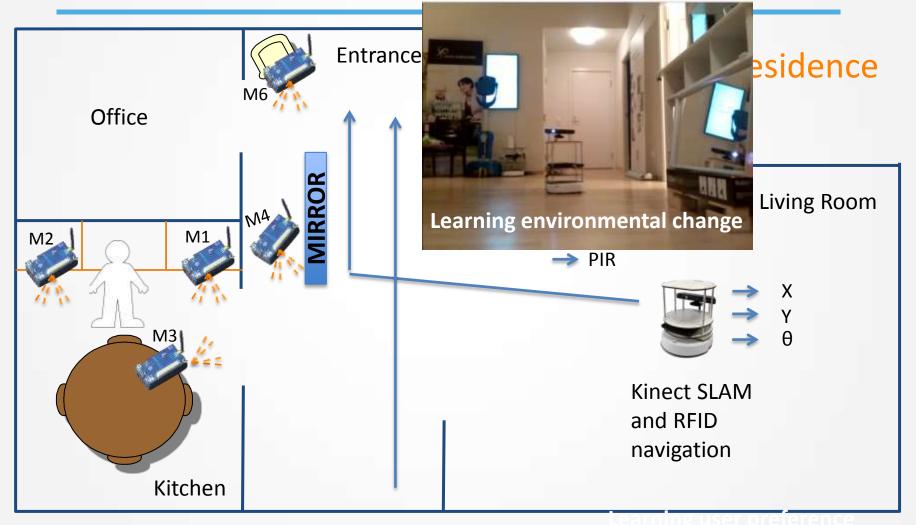


If neither RULE 1 nor RULE 2 fire,

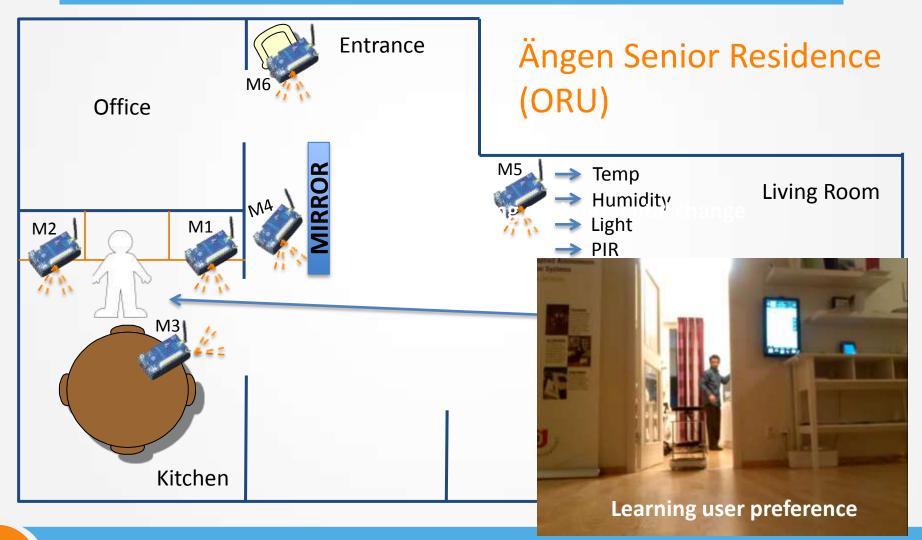
- I. Pick feature i in *F* that is minimally correlated with features in *SF*
- II. Pick feature j from those correlated to i that is also the maximally correlated with selected features in *SF*
- III. Add i to SF and j to DF



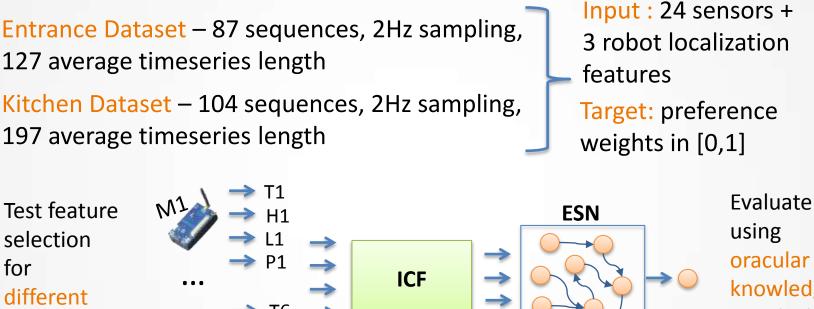
Experimental Scenario



Experimental Scenario



Datasets & Experimental Setup



Х

Evaluate using oracular knowledge on which features are relevant for each task

Experimental comparison with state-of-the-art CleVer algorithm (needs human supervision!)

input

features

Entrance Task – Selected Features

Configuration	ICF	CleVer-IT	CleVer -OPT
M3 + (Χ,Υ,θ)	Х, Ү, РЗ	L3, <mark>P3, Y</mark>	L3, <mark>P3</mark> , T3, <mark>Y</mark>
M3+M6+(X,Y,0)	Х, Ү, РЗ	L3, <mark>P6, X,</mark>	L3, <mark>P3, P6, X,</mark> 0
M4-M6 + (Χ,Υ,θ)	<mark>Y</mark> , P4, <mark>P6</mark> , L4	P4, L6, T6, 0	Ρ4, L6, T6, <mark>θ</mark>
M3-M6 + (X,Y,0)	X, Y, P3, P6	L3, <mark>P3</mark> , T5, θ	L3, T3, P4, <mark>P6</mark> , θ
M1-M6 + (Χ,Υ,θ)	<mark>X, Y</mark> , P1, P2, <mark>P3, P6</mark>	L1, P2, T2, L3, L6, 0	P2, L3, P4, L5, 0
	105		

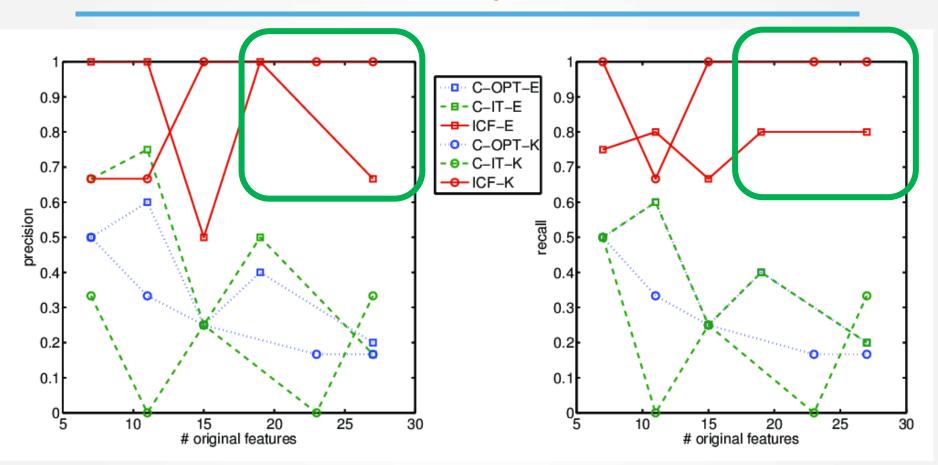
L = LightICF can identify relevant features evenP = PIRwhen many uninformative features areT = Temperaturepresent

Kitchen Task – Selected Features

Configuration	ICF	CleVer-IT	CleVer -OPT
M3 + (X,Y,0)	L3, <mark>P3</mark> , X	L3, <mark>X</mark> , Y	X , Y
M1+M3+(X,Υ,θ)	L1, <mark>P3, X</mark>	L3, T3, Y	L3, <mark>X</mark> , Y
M1-M3 + (Χ,Υ,θ)	P1, P2, P3, X	L1, L2, H2, <mark>X</mark>	L1, L2, H2, <mark>X</mark> , Y
M1-M5 + (Χ,Υ,θ)	P1, P2, P3, P4, P5, X	L1, L2, H2, L3, T3, L4	L1, <mark>P2</mark> , L3, T3, L4, H5
M1-M6 + (Χ,Υ,θ)	P1, P2, P3, P4, P5, X	T1, L2, <mark>P2</mark> , H2, L3, <mark>P4</mark>	T1, L2, H2, L3, <mark>P4</mark> , P6
L = Light P = PIR T = Temperature H = Humidity		Selected features can drastically change in different CleVer executions	

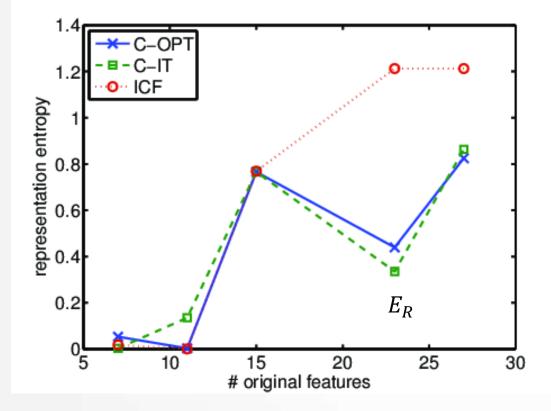


Precision-Recall Analysis



ICF proportion of FP and FN does not grow with the size of the search space

Kitchen Task – Representation Entropy



 E_R is minimal when all information is concentrated on a single feature

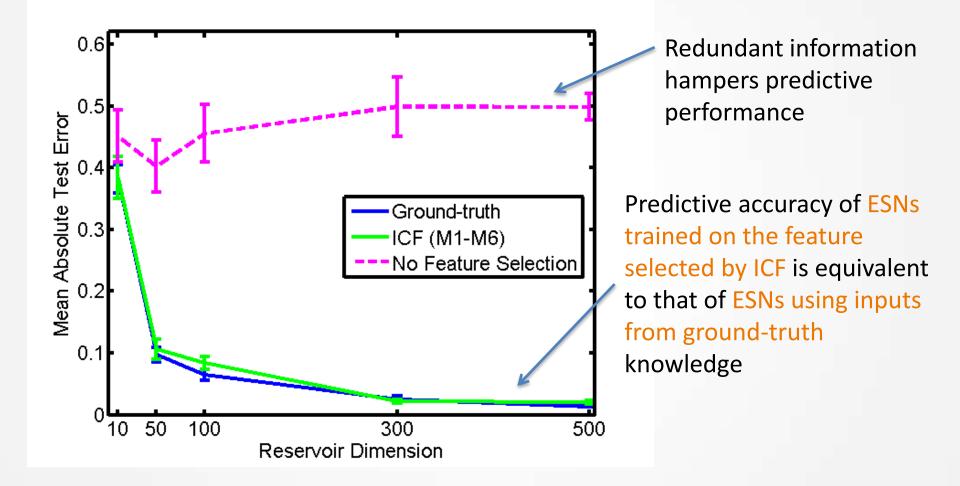
Representation entropy measures the amount of redundancy present in the selected feature subsets

$$E_R = -\sum_{i=1}^K \overline{\lambda}_i \log \overline{\lambda}_i$$

 λ_i normalized eigenvalue associated to the i-th selected feature



Kitchen Task – Predictive Performance



Conclusion & Future Works

- An efficient feature filter algorithm tailored to real-time pervasive computing applications
 - Noisy, often slowly changing, heterogeneous sensor timeseries
 - Provide unsupervised identification of non-redundant timeseries
 - Yield stable initialization-independent feature subsets
- Coming soon..
 - Two-phase feature selection mechanism
 - ICF filter to perform redundancy reduction



- ESNnigma supervised wrapper to optimize ESN predictive performance

ICF and CleVer Matlab code soon available www.di.unipi.it/~bacciu/icf

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www.fp7rubicon.eu